

## PEE6J001 VSLI DESIGN (4-0-0)

### Module – I 08 Hours

**Introduction:** Historical Perspective, VLSI Design Methodologies, VLSI Design Flow, Design Hierarchy, Concept of Regularity, Modularity and Locality, VLSI Design Styles, Computer-Aided Design Technology.

**Fabrication of MOSFETs:** Introduction, Fabrication Processes Flow – Basic Concepts, The CMOS n-Well Process, Layout Design Rules, Stick Diagrams, Full-Customs Mask Layout Design.

**MOS Transistor:** The Metal Oxide Semiconductor (MOS) Structure, The MOS System under External Bias, Structure and Operation of MOS Transistor (MOSFET), MOSFET Current-Voltage Characteristics, MOSFET Scaling and Small-Geometry Effects, MOSFET Capacitance.

(Chapter 1 to 3 of Text Book 1 and for Stick Diagram Text Book 2)

### Module – II 14 Hours

**MOS Inverters – Static Characteristics:** Introduction, Resistive-Load Inverters, Inverters with n-Type MOSFET Load, CMOS Inverter.

**MOS Inverters – Switching Characteristics and Interconnect Effects:** Introduction, Delay-Time Definitions, Calculation of Delay-Times, Inverter Design with Delay Constraints, Estimation of Interconnect Parasitics, Calculation of Interconnect Delay, Switching Power Dissipation of CMOS Inverters.

**Combinational MOS Logic Circuits:** Introduction, MOS Logic Circuits with Depletion nMOS Loads, CMOS Logic Circuits, Complex Logic Circuits, CMOS Transmission Gates (Pass Gates).

(Chapter 5 to 7 of Text Book 1)

### Module – III 18 Hours

**Sequential MOS Logic Circuits:** Introduction, Behaviour of Bistable Elements, SR Latch Circuits, Clocked Latch and Flip-Flop Circuits, CMOS D-Latch and Edge-Triggered Flip-Flop.

**Dynamic Logic Circuits:** Introduction, Basic Principles of Pass Transistor Circuits, Voltage Bootstrapping, Synchronous Dynamic Circuit Techniques, Dynamic CMOS Circuit Techniques, High Performance Dynamic CMOS Circuits.

**Semiconductor Memories:** Introduction, Dynamic Random Access Memory (DRAM), Static Random Access Memory (SRAM), Non-volatile Memory, Flash Memory.

**Design for Testability:** Introduction, Fault Types and Models, Ad Hoc Testable Design Techniques, Scan-Based Techniques, Built-In Self-Test (BIST) Techniques, Current Monitoring  $I_{DDQ}$  Test.

### Text Books:

1. Sung-Mo Kang and Yusuf Leblebici, *CMOS Digital Integrated Circuits: Analysis and Design*, 3<sup>rd</sup> Edn., Tata McGraw-Hill Publishing Company Limited, 2003.
2. K. Eshraghian and N.H.E. Weste, *Principles of CMOS VLSI Design – a Systems Perspective*, 2nd Edn., Addison Wesley, 1993.

### Reference Books:

1. Jan M. Rabaey, Anantha Chandrakasan, Borivoje Nikolic, *Digital Integrated Circuits – A Design Perspective*, 2nd Edn., Pearson Education, 2003.
2. Debaprasad Das, *VLSI Design*, Oxford University Press, 2015
3. Wayne Wolf, *Modern VLSI Design System – on – Chip Design*, 3rd Edn., Pearson Education, 2003.
4. John P. Uyemura, *CMOS Logic Circuit Design*, Springer (Kluwer Academic Publishers), 2001.
5. Ken Martin, *Digital Integrated Circuit Design*, Oxford University Press, 2000.